

FORM PTO-1449 (modified)  
 To: U.S. Department of Commerce  
 (PW FORM PAT-1449)  
 Patent and Trademark Office

Atty. Dkt. No.	M#	Client Ref.
	307720	P-1503.020-US

Applicant: STEVEN HANSEN
Appln. No.: <del>TO BE ASSIGNED</del> 10/773,397
Filing Date: February 9, 2004

Date: February 9, 2004

Page 1 of 1

Examiner: Unassigned Group Art Unit: Unassigned

#### U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 5,305,054	04/1994	SUZUKI et al.			
	BR 5,523,193	06/1996	NELSON			
	CR 6,049,660	04/2000	AHN et al.			
	DR 6,452,662	09/2002	MULKENS et al.			
	ER 6,463,403 B1	10/2002	BURDORF et al.			
	FR 6,466,304	10/2002	SMITH			
	GR 2002/0035461 A1	03/2002	CHANG et al.			
V	HR 2002/0167653 A1	11/2002	MULKENS et al.			
	IR 2003/0093251 A1	05/2003	CHANG			
JR						
KR						
LR						
MR						
NR						
OR						
PR						

#### FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
QR								
RR								
SR								
TR								
UR								
VR								
WR								
XR								
YR								
ZR								

#### OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

AAR			
BBR			
CCR			
DDR			

Examiner *Alan Mathews*

Date Considered: *8-7-2005*

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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		307720	P-1503.020-US
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Applicant: HANSEN		
Appln. No.: 10/773,397			
Filing Date: February 9, 2004			
Date: August 27, 2004	1	of	1
		Examiner: TBA	Group Art Unit: 1558

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

AUG 27 2004

Date: August 27, 2004

1 of

1

## **U.S. PATENT DOCUMENTS**

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
A1	AR	2003/0073013 A1	04/2003	Hsu et al.			
	BR						
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						

## FOREIGN PATENT DOCUMENTS

**OTHER** (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

MR					
NR					
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Examiner Alan Mathews

Date Considered: 8 - 5 - 2005

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	307720	P-1503.020-US
Applicant: HANSEN		
Appln. No.: 10/773,397		
Filing Date: February 9, 2004		
Date: May 10, 2004	Page <b>1</b> of <b>1</b>	Examiner: NOT ASSIGNED Group Art Unit: NOT ASSIGNED

### U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR	5,680,588	10/1997	Gortych et al.			
	BR	2002/0045106 A1	04/2002	Baselmans et al.			
	CR	2002/0062206 A1	05/2002	Liebchen			
	DR	2002/0152452 A1	10/2002	Socha			
	ER	2003/0082463 A1	05/2003	Laidig et al.			

### FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
						Enclosed	No

### OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

AM	FR	Burkhardt et al., "Illuminator Design for the Printing of Regular Contact Patterns," <i>Microelectronic Engineering</i> , Vol. 41, No. 42, 1998, pp. 91-96.					
	GR	Chen et al., "Practical Method for Full-Chip Optical Proximity Correction," <i>SPIE</i> , Vol. 3051, 1997, pp. 790-803.					
	HR	Chen et al., "Optical Proximity Correction for Intermediate-Pitch Features Using Sub-Resolution Scattering Bars," <i>Journal of Vacuum Science &amp; Technology B</i> , Vol. 15, No. 6, Nov/Dec 1997, pp. 2426-2433.					
	IR	Flagello et al., "Lithographic Lens Testing: Analysis of Measured Aerial Images, Interferometric Data and Photoresist Measurements," <i>SPIE Microlithography Seminar</i> , 1996.					
	JR	Flagello et al., "Towards a Comprehensive Control of Full-Field Image Quality in Optical Photolithography," <i>SPIE Microlithography Seminar</i> , March 1997.					
	KR	Gau et al., "Strategy to Manipulate the Optical Proximity Effect by Post-Exposure Bake Processing," <i>SPIE</i> , Vol. 3334, 1998, pp. 885-891.					
	LR	Gau et al., "The Customized Illumination Aperture Filter for Low k <sub>1</sub> Photolithography Process," <i>SPIE</i> , Vol. 4000, March 2000, pp. 271-282.					
	MR	Hsia et al., "Customized Off-Axis Illumination Aperture Filtering for Sub-0.18 μm KrF Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 427-434.					
	NR	Liu et al., "The Application of Alternating Phase-Shifting Masks to 140 nm Gate Patterning: Line Width Control Improvements and Design Optimization," <i>SPIE</i> , Vol. 3236, 1998, pp. 328-337.					
	OR	Smith et al., "Illumination Pupil Filtering Using Modified Quadrupole Apertures," <i>SPIE</i> , Vol. 3334, 1998, pp. 384-394.					
	PR	Suzuki et al., "Multilevel Imaging System Realizing k <sub>1</sub> =0.3 Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 396-407.					
	QR	Wong et al., "Level-Specific Lithography Optimization for 1-Gb DRAM," <i>IEEE Transactions on Semiconductor Manufacturing</i> , Vol. 13, No. 1, February 2000, pp. 76-87.					

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HANSEN - 10/773,397  
Docket No. 081468-0307720

APPENDIX

Examiner's Initials	First Inventor	Application No.	Filing Date	Enclosed
AM	Liebchen	10/705,234	November 12, 2003	<input checked="" type="checkbox"/> Specification <input checked="" type="checkbox"/> Drawings <input checked="" type="checkbox"/> Other: Claims

The Examiner's initials indicates he/she has considered the cited application relative to the subject application.

**DO NOT PRINT** the above information on the patent which results from the subject application.

*alan Mathews*

*Date Considered*

*8-7-2005*